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- Highest Performance Fixed-Point Digital Signal Processor (DSP) SM/SMJ320C6201B
  - 5-, 6.7-ns Instruction Cycle Time
  - 150 and 200-MHz Clock Rate
  - Eight 32-Bit Instructions/Cycle
  - 1200 and 1600 MIPS
- VelociTI<sup>™</sup> Advanced Very Long Instruction Word (VLIW) C62x<sup>™</sup> CPU Core
  - Eight Independent Functional Units:
    - Six ALUs (32-/40-Bit)
    - Two 16-Bit Multipliers (32-Bit Results)
  - Load-Store Architecture With 32 32-Bit General-Purpose Registers
  - Instruction Packing Reduces Code Size
  - All Instructions Conditional
- Instruction Set Features
  - Byte-Addressable (8-, 16-, 32-Bit Data)
  - 32-Bit Address Range
  - 8-Bit Overflow Protection
  - Saturation
  - Bit-Field Extract, Set, Clear
  - Bit-Counting
  - Normalization
- 1M-Bit On-Chip SRAM
  - 512K-Bit Internal Program/Cache (16K 32-Bit Instructions)
  - 512K-Bit Dual-Access Internal Data (64K Bytes) Organized as Two Blocks for Improved Concurrency
- 32-Bit External Memory Interface (EMIF)
  - Glueless Interface to Synchronous Memories: SDRAM and SBSRAM
  - Glueless Interface to Asynchronous Memories: SRAM and EPROM
- Four-Channel Bootloading Direct-Memory-Access (DMA) Controller with an Auxiliary Channel
- 16-Bit Host-Port Interface (HPI)
   Access to Entire Memory Map

GLP 429-PIN BALL GRID ARRAY (BGA) PACKAGE (BOTTOM VIEW)



- Two Multichannel Buffered Serial Ports (McBSPs)
  - Direct Interface to T1/E1, MVIP, SCSA Framers
  - ST-Bus-Switching Compatible
  - Up to 256 Channels Each
  - AC97-Compatible
  - Serial Peripheral Interface (SPI) Compatible (Motorola<sup>™</sup>)
- Two 32-Bit General-Purpose Timers
- Flexible Phase-Locked Loop (PLL) Clock Generator
- IEEE-1149.1 (JTAG<sup>†</sup>) Boundary-Scan Compatible
- 429-Pin BGA Package (GLP Suffix)
- CMOS Technology
   0.18-μm/5-Level Metal Process
- 3.3-V I/Os, 1.8-V Internal



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<sup>†</sup> IEEE Standard 1149.1-1990 Standard-Test-Access Port and Boundary Scan Architecture.

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#### description

The 320C6201B DSP is a member of the fixed-point DSP family in the 320C6000 platform. The SM/SMJ320C6201B (C6201B) device is based on the high-performance, advanced VelociTI very-long-instruction-word (VLIW) architecture developed by Texas Instruments (TI<sup>™</sup>), making this DSP an excellent choice for multichannel and multifunction applications. With performance of up to 1600 million instructions per second (MIPS) at a clock rate of 200 MHz, the C6201B offers cost-effective solutions to high-performance DSP programming challenges. The C6201B is a newer revision of the C6201. The C6201B DSP possesses the operational flexibility of high-speed controllers and the numerical capability of array processors. This processor has 32 general-purpose registers of 32-bit word length and eight highly independent functional units. The eight functional units provide six arithmetic logic units (ALUs) for a high degree of parallelism and two 16-bit multipliers for a 32-bit result. The C6201B can produce two multiply-accumulates (MACs) per cycle—for a total of 400 million MACs per second (MMACS). The C6201B DSP also has application-specific hardware logic, on-chip memory, and additional on-chip peripherals.

The C6201B includes a large bank of on-chip memory and has a powerful and diverse set of peripherals. Program memory consists of a 64K-byte block that is user-configurable as cache or memory-mapped program space. Data memory of the C6201B consists of two 32K-byte blocks of RAM for improved concurrency. The peripheral set includes two multichannel buffered serial ports (McBSPs), two general-purpose timers, a host-port interface (HPI), and a glueless external memory interface (EMIF) capable of interfacing to SDRAM or SBSRAM and asynchronous peripherals.

The C6201B has a complete set of development tools which includes: a new C compiler, a third-party Ada 95 compiler, an assembly optimizer to simplify programming and scheduling, and a Windows<sup>™</sup> debugger interface for visibility into source code execution.

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#### device characteristics

Table 1 provides an overview of the C62x DSP. The table shows significant features of each device, including the capacity of on-chip RAM, the peripherals, the execution time, and the package type with pin count.

CHARACTERISTICS	DESCRIPTION
Device Number	320C6201B
On-Chip Memory	512-Kbit Program Memory 512-Kbit Data Memory (organized as two blocks)
Peripherals	2 Multichannel Buffered Serial Ports (McBSPs) 2 General-Purpose Timers Host-Port Interface (HPI) External Memory Interface (EMIF)
Cycle Time	6.7 ns (320C6201B 150 MHz), 5 ns (320C6201B 200 MHz)
Package Type	27 mm × 27 mm, 429-Pin Ceramic D-BGA (GLP)
Nominal Voltage	1.8 V Core 3.3 V I/O

#### Table 1. Characteristics of the C6201B Processor

#### functional block diagram





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#### **CPU description**

The CPU fetches VelociTI advanced very-long instruction words (VLIW) (256 bits wide) to supply up to eight 32-bit instructions to the eight functional units during every clock cycle. The VelociTI VLIW architecture features controls by which all eight units do not have to be supplied with instructions if they are not ready to execute. The first bit of every 32-bit instruction determines if the next instruction belongs to the same execute packet as the previous instruction, or whether it should be executed in the following clock as a part of the next execute packet. Fetch packets are always 256 bits wide; however, the execute packets can vary in size. The variable-length execute packets are a key memory-saving feature, distinguishing the C62x CPU from other VLIW architectures.

The CPU features two sets of functional units. Each set contains four units and a register file. One set contains functional units .L1, .S1, .M1, and .D1; the other set contains units .D2, .M2, .S2, and .L2. The two register files each contain 1632-bit registers for a total of 32 general-purpose registers. The two sets of functional units, along with two register files, compose sides A and B of the CPU (see Figure 1 and Figure 2). The four functional units on each side of the CPU can freely share the 16 registers belonging to that side. Additionally, each side features a single data bus connected to all the registers on the other side, by which the two sets of functional units can access data from the register files on the opposite side. While register access by functional units on the same side of the CPU as the register file can service all the units in a single clock cycle, register access using the register file across the CPU supports one read and one write per cycle.

Another key feature of the C62x CPU is the load/store architecture, where all instructions operate on registers (as opposed to data in memory). Two sets of data-addressing units (.D1 and .D2) are responsible for all data transfers between the register files and the memory. The data address driven by the .D units allows data addresses generated from one register file to be used to load or store data to or from the other register file. The C62x CPU supports a variety of indirect addressing modes using either linear- or circular-addressing modes with 5- or 15-bit offsets. All instructions are conditional, and most can access any one of the 32 registers. Some registers, however, are singled out to support specific addressing or to hold the condition for conditional instructions (if the condition is not automatically "true"). The two .M functional units are dedicated for multiplies. The two .S and .L functional units perform a general set of arithmetic, logical, and branch functions with results available every clock cycle.

The processing flow begins when a 256-bit-wide instruction fetch packet is fetched from a program memory. The 32-bit instructions destined for the individual functional units are "linked" together by "1" bits in the least significant bit (LSB) position of the instructions. The instructions that are "chained" together for simultaneous execution (up to eight in total) compose an execute packet. A "0" in the LSB of an instruction breaks the chain, effectively placing the instructions that follow it in the next execute packet. If an execute packet crosses the fetch packet boundary (256 bits wide), the assembler places it in the next fetch packet, while the remainder of the current fetch packet is padded with NOP instructions. The number of execute packets within a fetch packet can vary from one to eight. Execute packets are dispatched to their respective functional units at the rate of one per clock cycle and the next 256-bit fetch packet is not fetched until all the execute packets from the current fetch packet have been dispatched. After decoding, the instructions simultaneously drive all active functional units for a maximum execution rate of eight instructions every clock cycle. While most results are stored in 32-bit registers, they can be subsequently moved to memory as bytes or half-words as well. All load and store instructions are byte-, half-word, or word-addressable.



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#### **CPU description (continued)**



Figure 1. 320C62x CPU Block Diagram



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# CPU description (continued)







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#### signal groups description





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#### signal groups description (continued)



Figure 4. Peripheral Signals



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	Signal Descriptions				
SIGNA NAME	L NO.	TYPE <sup>†</sup>	DESCRIPTION		
			CLOCK/PLL		
CLKIN	A14	I	Clock Input		
CLKOUT1	Y6	0	Clock output at full device speed		
CLKOUT2	V9	0	Clock output at half of device speed		
CLKMODE1	B17		Clock mode select		
CLKMODE0	C17	1	<ul> <li>Selects whether the output clock frequency = input clock freq x4 or x1</li> </ul>		
PLLFREQ3	C13		PLL frequency range (3, 2, and 1)		
PLLFREQ2	G11	1	• The target range for CLKOUT1 frequency is determined by the 3-bit value of the PLLFREQ pins.		
PLLFREQ1	F11				
PLLV <sup>‡</sup>	D12	A§	PLL analog $V_{CC}$ connection for the low-pass filter		
PLLG <sup>‡</sup>	G10	A§	PLL analog GND connection for the low-pass filter		
PLLF	C12	A§	PLL low-pass filter connection to external components and a bypass capacitor		
			JTAG EMULATION		
TMS	K19	I	JTAG test port mode select (features an internal pull-up)		
TDO	R12	O/Z	JTAG test port data out		
TDI	R13	I	JTAG test port data in (features an internal pull-up)		
ТСК	M20	I	JTAG test port clock		
TRST	N18	I	JTAG test port reset (features an internal pull-down)		
EMU1	R20	I/O/Z	Emulation pin 1, pull-up with a dedicated 20-k $\Omega$ resistor		
EMU0	T18	I/O/Z	Emulation pin 0, pull-up with a dedicated 20-k $\Omega$ resistor		
			RESET AND INTERRUPTS		
RESET	J20	I	Device reset		
NMI	K21	I	Nonmaskable interrupt <ul> <li>Edge-driven (rising edge)</li> </ul>		
EXT_INT7	R16				
EXT_INT6	P20		External interrupts		
EXT INT5	R15	1	Edge-driven (rising edge)		
EXT_INT4	R18				
IACK	R11	0	Interrupt acknowledge for all active interrupts serviced by the CPU		
INUM3	T19				
INUM2	T20	1	Active interrupt identification number		
INUM1	T14	0	<ul> <li>Valid during IACK for all active interrupts (not just external)</li> <li>Encoding order follows the interrupt service fetch packet ordering</li> </ul>		
INUM0	T16	1	Encounty order tonows the interrupt service letter packet ordening		
			LITTLE ENDIAN/BIG ENDIAN		
LENDIAN	G20	I	If high, selects little-endian byte/half-word addressing order within a word If low, selects big-endian addressing		
			POWER DOWN STATUS		
PD	D19	0	Power-down mode 2 or 3 (active if high)		
		Link Inc.			

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

<sup>‡</sup> PLLV and PLLG signals are not part of external voltage supply or ground. See the CLOCK/PLL documentation for information on how to connect those pins.

<sup>§</sup> A = Analog Signal (PLL Filter)



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### Signal Descriptions (Continued)

SIGNAL						
NAME	NO.	TYPE†	DESCRIPTION			
	HOST PORT INTERFACE (HPI)					
HINT	H2	O/Z	Host interrupt (from DSP to host)			
HCNTL1	J6	I	Host control - selects between control, address or data registers			
HCNTL0	H6	I	Host control - selects between control, address or data registers			
HHWIL	E4	I	Host halfword select - first or second halfword (not necessarily high or low order)			
HBE1	G6	I	Host byte select within word or half-word			
HBE0	F6	I	Host byte select within word or half-word			
HR/W	D4	I	Host read or write select			
HD15	D11					
HD14	B11					
HD13	A11					
HD12	G9					
HD11	D10					
HD10	A10					
HD9	C10		Host port data (used for transfer of data, address and control)			
HD8	B9	107				
HD7	F9	I/O/Z				
HD6	C9					
HD5	A9					
HD4	B8					
HD3	D9					
HD2	D8					
HD1	B7					
HD0	C7					
HAS	L6	I	Host address strobe			
HCS	C5	I	Host chip select			
HDS1	C4	I	Host data strobe 1			
HDS2	K6	I	Host data strobe 2			
HRDY	HЗ	0	Host ready (from DSP to host)			
			BOOT MODE			
BOOTMODE4	B16					
BOOTMODE3	G14					
BOOTMODE2	F15	I	Boot mode			
BOOTMODE1	C18					
BOOTMODE0	D17					



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	Signal Descriptions (Continued)				
SIGNAL NAME	NO.	TYPE <sup>†</sup>	DESCRIPTION		
		EI	MIF - CONTROL SIGNALS COMMON TO ALL TYPES OF MEMORY		
CE3	Y5	O/Z			
CE2	V3	O/Z	Memory space enables		
CE1	T6	O/Z	Enabled by bits 24 and 25 of the word address		
CE0	U2	O/Z	Only one asserted during any external data access		
BE3	R8	O/Z	Byte enable control		
BE2	Т3	O/Z	Decoded from the two lowest bits of the internal address		
BE1	T2	O/Z	Byte write enables for most types of memory		
BE0	R2	O/Z	Can be directly connected to SDRAM read and write mask signal (SDQM)		
			EMIF - ADDRESS		
EA21	L4				
EA20	L3				
EA19	J2				
EA18	J1				
EA17	K1				
EA16	K2				
EA15	L2				
EA14	L1				
EA13	M1				
EA12	M2				
EA11	M6	O/Z	External address (word address)		
EA10	N4	]			
EA9	N1	]			
EA8	N2	]			
EA7	N6	]			
EA6	P4	]			
EA5	P3	]			
EA4	P2	]			
EA3	P1	]			
EA2	P6				



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	Signal Descriptions (Continued)				
SIGNAL NAME	NO.	TYPE <sup>†</sup>	DESCRIPTION		
			EMIF - DATA		
ED31	U18				
ED30	U20				
ED29	T15				
ED28	V18				
ED27	V17				
ED26	V16				
ED25	T12				
ED24	W17				
ED23	T13				
ED22	Y17	1			
ED21	T11	1			
ED20	Y16	1			
ED19	W15				
ED18	V14				
ED17	Y15				
ED16	R9	1			
ED15	Y14	I/O/Z	External data		
ED14	V13				
ED13	AA13				
ED12	T10				
ED11	Y13				
ED10	W12				
ED9	Y12				
ED8	Y11				
ED7	V10				
ED6	AA10				
ED5	Y10	1			
ED4	W10	1			
ED3	Y9	]			
ED2	AA9	]			
ED1	Y8	]			
ED0	W9	]			
			EMIF - ASYNCHRONOUS MEMORY CONTROL		
ARE	R7	O/Z	Asynchronous memory read enable		
AOE	T7	O/Z	Asynchronous memory output enable		
AWE	V5	O/Z	Asynchronous memory write enable		
ARDY	R4		Asynchronous memory ready input		



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	Signal Descriptions (Continued)						
SIGNAL NAME	NO.	TYPE <sup>†</sup>	DESCRIPTION				
	EMIF - SYNCHRONOUS BURST SRAM CONTROL						
SSADS	V8	O/Z	SBSRAM address strobe				
SSOE	W7	O/Z	SBSRAM output enable				
SSWE	Y7	O/Z	SBSRAM write enable				
SSCLK	AA8	O/Z	SBSRAM clock				
			EMIF - SYNCHRONOUS DRAM CONTROL				
SDA10	V7	O/Z	SDRAM address 10 (separate for deactivate command)				
SDRAS	V6	O/Z	SDRAM row address strobe				
SDCAS	W5	O/Z	SDRAM column address strobe				
SDWE	T8	O/Z	SDRAM write enable				
SDCLK	T9	O/Z	SDRAM clock				
			EMIF - BUS ARBITRATION				
HOLD	R6	I	Hold request from the host				
HOLDA	B15	0	Hold request acknowledge to the host				
			TIMERS				
TOUT1	G2	0	Timer 1 or general-purpose output				
TINP1	K3	I	Timer 1 or general-purpose input				
TOUT0	M18	0	Timer 0 or general-purpose output				
TINP0	J18	I	Timer 0 or general-purpose input				
			DMA ACTION COMPLETE				
DMAC3	E18						
DMAC2	F19						
DMAC1	E20	0	DMA action complete				
DMAC0	G16						
		-	MULTICHANNEL BUFFERED SERIAL PORT 1 (McBSP1)				
CLKS1	F4	I	External clock source (as opposed to internal)				
CLKR1	H4	I/O/Z	Receive clock				
CLKX1	J4	I/O/Z	Transmit clock				
DR1	E2	I	Receive data				
DX1	G4	O/Z	Transmit data				
FSR1	F3	I/O/Z	Receive frame sync				
FSX1	F2	I/O/Z	Transmit frame sync				



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### **Signal Descriptions (Continued)**

SIGNA	\L	T (DEt	DECODIDATION			
NAME	NO.	TYPE <sup>†</sup>	DESCRIPTION			
	MULTICHANNEL BUFFERED SERIAL PORT 0 (McBSP0)					
CLKS0	K18	I	External clock source (as opposed to internal)			
CLKR0	L21	I/O/Z	Receive clock			
CLKX0	K20	I/O/Z	Transmit clock			
DR0	J21	I	Receive data			
DX0	M21	O/Z	Transmit data			
FSR0	P16	I/O/Z	Receive frame sync			
FSX0	N16	I/O/Z	Transmit frame sync			
			RESERVED FOR TEST			
RSV0	N21	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor			
RSV1	K16	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor			
RSV2	B13	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor			
RSV3	B14	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor			
RSV4	F13	I	Reserved for testing, <i>pull-down</i> with a dedicated 20-k $\Omega$ resistor			
RSV5	C15	0	Reserved (leave unconnected, <i>do not</i> connect to power or ground)			
RSV6	F7	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor			
RSV7	D7	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor			
RSV8	B5	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor			
RSV9	F16	0	Reserved (leave unconnected, <i>do not</i> connect to power or ground)			
			SUPPLY VOLTAGE PINS			
	C14					
	C8					
	E19					
	E3					
	H11					
	H13					
	H9					
	J10					
	J12					
	J14					
DV <sub>DD</sub>	J19	S	3.3-V supply voltage			
	J3					
	J8					
	K11					
	K13					
	K15					
	K7					
	K9					
	L10					
	L12					
<u> </u>	L14		edance. S = Supply Voltage. GND = Ground			



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Signal Descriptions (Continued)					
SIGNAL NAME	NO.	TYPE <sup>†</sup>	DESCRIPTION		
	NO.		SUPPLY VOLTAGE PINS (CONTINUED)		
	L8				
	M11				
	M13				
	M15				
	M7				
	M9				
	N10				
	N12				
	N14				
DV <sub>DD</sub>	N19	S	3.3-V supply voltage		
	N3				
	N8				
	P11				
	P13				
	P9 U19				
	U3	-			
	W14				
	W14 W8				
	A12				
	A13				
	B10				
	B12				
	B6				
	D15				
	D16				
	F10				
	F14				
CV <sub>DD</sub>	F8	s	1.8-V supply voltage		
00 י	G13		1.0-v supply voltage		
	G7				
	G8				
	K4				
	M3				
	M4				
	A3				
	A5				
	A7 A16				
		llich Imn	edance. S = Supply Voltage, GND = Ground		



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	Signal Descriptions (Continued)					
SIGNAL NAME	NO.	TYPE <sup>†</sup>	DESCRIPTION			
			SUPPLY VOLTAGE PINS (CONTINUED)			
	A18 AA4 AA5 AA17 AA19 B2 B4 B19 C1 C3 C20 C20 C20 C20 C20 C20 C20 C20 C20 C20	S	1.8-V supply voltage			



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	Signal Descriptions (Continued)						
SIGNA NAME	L NO.	TYPE <sup>†</sup>	DESCRIPTION				
			SUPPLY VOLTAGE PINS (CONTINUED)				
CVDD	T1         T5         T17         U6         U8         U10         U12         U14         U16         U21         V1         V20         W2         W19         W21         Y3         Y18         Y20         AA11         AA12         F20         G18         H16         H18         L19         L20         N20         P18         P19         R10         R14         U4         V11         V12         V15         W13	S	1.8-V supply voltage				



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Signal Descriptions (Continued)						
	SIGNAL DESCRIPTION					
NAME	NO.		GROUND PINS			
	C11					
	C16					
	C6					
	D5					
	G3					
	H10					
	H12					
	H14					
	H7					
	H8					
	J11					
	J13					
	J7					
	J9 K8					
	L7					
	L7 L9					
	M8					
	N7	1				
V <sub>SS</sub>	R3	GND	Ground pins			
- 55	A4					
	A6					
	A8					
	A15					
	A17					
	A19					
	AA3					
	AA5					
	AA7					
	AA14					
	AA16					
	AA18 B3					
	B3 B18					
	B18					
	C2					
	C19					
	C21					
	D1					
$^{\dagger}$ I – Input O – O		High Impe	edance, S = Supply Voltage, GND = Ground			



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			Signal Descriptions (Continued)
SIGNAI NAME	L NO.	TYPE <sup>†</sup>	DESCRIPTION
			GROUND PINS (CONTINUED)
V <sub>SS</sub>	D20 E5 E7 E9 E11 E13 E15 E17 E21 F1 G5 G17 G21 H1 J5 J17 C2 L5 L17 N5 N17 P21 R1 R5 R17 T21 R1 R5 R17 T21 U1 U1 U5 U17 U2 U11 U13 U15 U17 V2 V21	GND	Ground pins

 $^{\dagger}$  I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



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			Signal Descriptions (Continued)
SIGNAL NAME	NO.	TYPE <sup>†</sup>	DESCRIPTION
			GROUND PINS (CONTINUED)
V <sub>SS</sub>	W1         W3         W20         Y2         Y4         Y19         F18         G19         H15         J15         J16         K10         K12         K14         L11         L13         L15         M10         M12         M14         N13         N15         N9         P10         P12         P14         P15         P7         P8         R19         T4         W11         W16         W6	GND	Ground pins



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			Signal Descriptions (Continued)
SIGNA NAME	L NO.	TYPE <sup>†</sup>	DESCRIPTION
		1	REMAINING UNCONNECTED PINS
	D13		
	D14		
	D18		
	D3		
	D6		
	F12		
	G12		
	G15		
NC	H19		Unconnected pins
110	H20		
	H21		
	L16		
	M16		
	M19		
	V19		
	V4		
	W18		
	W4		



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#### development support

Texas Instruments offers an extensive line of development tools for the C6000 generation of DSPs, including tools to evaluate the performance of the processors, generate code, develop algorithm implementations, and fully integrate and debug software and hardware modules.

The following products support development of C6000-based applications:

#### Software Development Tools:

Assembly optimizer Assembler/Linker Simulator Optimizing ANSI C compiler Application algorithms C/Assembly debugger and code profiler

#### Hardware Development Tools:

Extended development system (XDS<sup>™</sup>) emulator (supports C6000 multiprocessor system debug) EVM (Evaluation Module)

The *TMS320 DSP Development Support Reference Guide* (SPRU011) contains information about development-support products for all TMS320 family member devices, including documentation. See this document for further information on TMS320 documentation or any TMS320 support products from Texas Instruments. An additional document, the *TMS320 Third-Party Support Reference Guide* (SPRU052), contains information about TMS320-related products from other companies in the industry. To receive TMS320 literature, contact the Product Information Center at (800) 477-8924.

See Table 2 for a complete listing of development-support tools for the C6000. For information on pricing and availability, contact the nearest TI field sales office or authorized distributor.

DEVELOPMENT TOOL	PLATFORM	PART NUMBER
Software         Ada 95 Compiler <sup>†</sup> Sun Solaris 2.3™‡       AD0345AS8500RF - Single User AD0345BS8500RF - Multi-user         C Compiler/Assembler/Linker/Assembly Optimizer       Win32™       TMDX3246855-07         C Compiler/Assembler/Linker/Assembly Optimizer       SPARC™ Solaris™       TMDX3246855-07         Simulator       Win32       TMDX3246851-07         Simulator       SPARC Solaris       TMDS3246851-07         XDS510™ Debugger/Emulation Software       Win32, Windows NT™       TMDX324016X-07         Hardware         XDS510 Emulator <sup>§</sup> PC       TMDS00510         XDS510 Emulator <sup>¶</sup> SCSI       TMDS00510WS         XDS510WS™ Emulator <sup>¶</sup> SCSI       TMDS00510WS		
Ada 95 Compiler <sup>†</sup>	Sun Solaris 2.3™ <sup>‡</sup>	0
C Compiler/Assembler/Linker/Assembly Optimizer	Win32™	TMDX3246855-07
C Compiler/Assembler/Linker/Assembly Optimizer	SPARC <sup>™</sup> Solaris <sup>™</sup>	TMDX324655-07
Simulator	Win32	TMDS3246851-07
Simulator	SPARC Solaris	TMDS3246551-07
XDS510 <sup>™</sup> Debugger/Emulation Software	Win32, Windows NT™	TMDX324016X-07
	Hardware	
XDS510 Emulator§	PC	TMDS00510
XDS510WS <sup>™</sup> Emulator <sup>¶</sup>	SCSI	TMDS00510WS
	Software/Hardware	
EVM Evaluation Kit	PC/Win95/Windows NT	TMDX3260A6201
EVM Evaluation Kit (including TMDX3246855-07)	PC/Win95/Windows NT	TMDX326006201

#### Table 2. 320C6000 Development-Support Tools

<sup>†</sup> Contact IRVINE Compiler Corporation (949) 250-1366 to order.

<sup>‡</sup> NT support estimated availability 1Q00.

§ Includes XDS510 board and JTAG emulation cable. TMDX324016X-07 C-source Debugger/Emulation software is not included.

<sup>¶</sup> Includes XDS510WS box, SCSI cable, power supply, and JTAG emulation cable.

XDS, XDS510, and XDS510WS are trademarks of Texas Instruments Incorporated.

Win32 and Windows NT are trademarks of Microsoft Corporation. SPARC is a trademark of SPARC International, Inc.

Solaris is a trademark of SPARC International, Il Solaris is a trademark of Sun Microsystems, Inc.



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#### device and development-support tool nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all TMS320 devices and support tools. Each TMS320 member has one of three prefixes: SMX, SM, or SMJ. Texas Instruments recommends two of three possible prefix designators for support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (SMX/TMDX) through fully qualified production devices/tools (SMJ/TMDS). This development flow follows.

Device development evolutionary flow:

- **SMX** Experimental device that is not necessarily representative of the final device's electrical specifications, 25°C tested, military/industrial ceramic dimpled Ball Grid Array package
- SM Fully TI-qualified production device; offered in extended temperature ranges: -40°C to +90°C (S range), and -55°C to +115°C (W range); in ceramic dimpled BGA package
- **SMJ** Fully SMD-qualified production device, -55°C to +115°C (W temperature range), in the ceramic dimpled Ball Grid Array package processed to MIL-PRF-38535

Support tool development evolutionary flow:

- **TMDX** Development-support product that has not yet completed Texas Instruments internal qualification testing.
- TMDS Fully qualified development-support product

TMX and TMP devices and TMDX development-support tools are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

TMS devices and TMDS development-support tools have been characterized fully, and the quality and reliability of the device have been demonstrated fully. TI's standard warranty applies.

Predictions show that prototype devices (SMX or SM) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (GLP) and the device speed range in megahertz (for example, 15 is 150 MHz). Figure 5 provides a legend for reading the complete device name.



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#### device and development-support tool nomenclature (continued)



<sup>†</sup> BGA = Ball Grid Array

#### Figure 5. TMS320 Device Nomenclature (Including SMJ320C6201B)

#### documentation support

Extensive documentation supports all TMS320 family generations of devices from product announcement through applications development. The types of documentation available include: data sheets, such as this document, with design specifications; complete user's reference guides for all devices; technical briefs; development-support tools; and hardware and software applications. The following is a brief, descriptive list of support documentation specific to the C6x<sup>TM</sup> devices:

The *TMS320C6000 CPU and Instruction Set Reference Guide* (literature number SPRU189) describes the C6000 CPU architecture, instruction set, pipeline, and associated interrupts.

The *TMS320C6000 Peripherals Reference Guide* (literature number SPRU190) describes the functionality of the peripherals available on C6x devices, such as the external memory interface (EMIF), host-port interface (HPI), multichannel buffered serial ports (McBSPs), direct-memory-access (DMA), enhanced direct-memory-access (EDMA) controller, expansion bus (XB), clocking and phase-locked loop (PLL); and power-down modes. This guide also includes information on internal data and program memories.

The *TMS320C6000 Programmer's Guide* (literature number SPRU198) describes ways to optimize C and assembly code for C6x devices and includes application program examples.

The *TMS320C6x C Source Debugger User's Guide* (literature number SPRU188) describes how to invoke the C6x simulator and emulator versions of the C source debugger interface and discusses various aspects of the debugger, including: command entry, code execution, data management, breakpoints, profiling, and analysis.

The *TMS320C6x Peripheral Support Library Programmer's Reference* (literature number SPRU273) describes the contents of the C6x peripheral support library of functions and macros. It lists functions and macros both by header file and alphabetically, provides a complete description of each, and gives code examples to show how they are used.

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#### documentation support (continued)

*TMS320C6000 Assembly Language Tools User's Guide* (literature number SPRU186) describes the assembly language tools (assembler, linker, and other tools used to develop assembly language code), assembler directives, macros, common object file format, and symbolic debugging directives for the C6000 generation of devices.

The *TMS320C6x Evaluation Module Reference Guide* (literature number SPRU269) provides instructions for installing and operating the C6x evaluation module. It also includes support software documentation, application programming interfaces, and technical reference material.

*TMS320C62x Multichannel Evaluation Module User's Guide* (literature number SPRU285) provides instructions for installing and operating the C62x multichannel evaluation module. It also includes support software documentation, application programming interfaces, and technical reference material.

*TMS320C62x Multichannel Evaluation Module Technical Reference* (SPRU308) provides provides technical reference information for the C62x multichannel evaluation module (McEVM). It includes support software documentation, application programming interface references, and hardware descriptions for the C62x McEVM.

*TMS320C6000 DSP/BIOS User's Guide* (literature number SPRU303) describes how to use DSP/BIOS tools and APIs to analyze embedded real-time DSP applications.

*Code Composer User's Guide* (literature number SPRU296) explains how to use the Code Composer development environment to build and debug embedded real-time DSP applications.

*Code Composer Studio Tutorial* (literature number SPRU301) introduces the Code Composer Studio integrated development environment and software tools.

The *TMS320C6000 Technical Brief* (literature number SPRU197) gives an introduction to the C62x/C67x devices, associated development tools, and third-party support.

A series of DSP textbooks is published by Prentice-Hall and John Wiley & Sons to support DSP research and education. The TMS320 newsletter, *Details on Signal Processing*, is published quarterly and distributed to update TMS320 customers on product information. The TMS320 DSP bulletin board service (BBS) provides access to information pertaining to the TMS320 family, including documentation, source code, and object code for many DSP algorithms and utilities. The BBS can be reached at 281/274-2323.

Information regarding TI DSP products is also available on the Worldwide Web at http://www.ti.com uniform resource locator (URL).



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#### clock PLL

All of the C62x clocks are generated from a single source through the CLKIN pin. This source clock either drives the PLL, which generates the internal CPU clock, or bypasses the PLL to become the CPU clock.

To use the PLL to generate the CPU clock, the filter circuit shown in Figure 6 must be properly designed. For the C6201B, it must be powered by the I/O voltage (3.3 V).

To configure the C62x PLL clock for proper operation, see Figure 6 and Table 3. To minimize the clock jitter, a single clean power supply should power both the C62x device and the external clock oscillator circuit. The minimum CLKIN rise and fall times should also be observed. See the *input and output clocks* section for input clock timing requirements. Guidelines for EMI filter selection are as follows: maximum attenuation frequency = 20-30 MHz, maximum dB attenuation = 45-50 db, and minimum dB attenuation above 30 MHz = 20 dB.



- NOTES: A. For the C6201B CLKMODE x4, values for C1, C2, and R1 are fixed and apply to all valid frequency ranges of CLKIN and CLKOUT.
   B. For CLKMODE x1, the PLL is bypassed and all six external PLL components can be removed. For this case, the PLLV terminal has to be connected to a clean supply and the PLLG and PLLF terminals should be tied together.
  - C. Due to overlap of frequency ranges when choosing the PLLFREQ, more than one frequency range can contain the CLKOUT1 frequency. Choose the lowest frequency range that includes the desired frequency. For example, for CLKOUT1 = 133 MHz, a PLLFREQ value of 000b should be used for the C6201B. For CLKOUT1 = 200 MHz, PLLFREQ should be set to 001b for the C6201B. PLLFREQ values other than 000b, 001b, and 010b are reserved.
  - D. For the C6201B, the 3.3-V supply for the EMI filter (and PLLV) must be from the same 3.3-V power plane supplying the I/O voltage, DV<sub>DD</sub>.

#### Figure 6. PLL Block Diagram



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#### clock PLL (continued)

CLKMODE	CLKIN RANGE (MHz)	CPU CLOCK FREQUENCY (CLKOUT1) RANGE (MHz)	CLKOUT2 RANGE (MHz)	R1 (Ω)	C1 (nF)	C2 (pF)	TYPICAL LOCK TIME (μs) <sup>†</sup>
x4	12.5-50	50-200	25-100	60.4	27	560	75

#### Table 3. 320C6201B PLL Component Selection Table

<sup>†</sup> Under some operating conditions, the maximum PLL lock time may vary as much as 150% from the specified typical value. For example, if the typical lock time is specified as 100 μs, the maximum value may be as long as 250 μs.

#### power supply sequencing

TI DSPs do not require specific power sequencing between the core supply and the I/O supply. However, systems should be designed to ensure that neither supply is powered up for extended periods of time if the other supply is below the proper operating voltage.

#### system-level design considerations

System-level design considerations, such as bus contention, may require supply sequencing to be implemented. In this case, the core supply should be powered up at the same time as, or prior to (and powered down after), the I/O buffers. This is to ensure that the I/O buffers receive valid inputs from the core before the output buffers are powered up, thus, preventing bus contention with other chips on the board.

#### power-supply design considerations

For systems using the C6000<sup>™</sup> DSP platform of devices, the core supply may be required to provide in excess of 2 A per DSP until the I/O supply is powered up. This extra current condition is a result of uninitialized logic within the DSP(s) and is corrected once the CPU sees an internal clock pulse. With the PLL enabled, as the I/O supply is powered on, a clock pulse is produced stopping the extra current draw from the supply. With the PLL disabled, an external clock pulse may be required to stop this extra current draw. A normal current state returns once the I/O power supply is turned on and the CPU sees a clock pulse. Decreasing the amount of time between the core supply power up and the I/O supply power up can minimize the effects of this current draw.

A dual-power supply with simultaneous sequencing, such as available with TPS563xx controllers or PT69xx plug-in power modules, can be used to eliminate the delay between core and I/O power up [see the *Using the TPS56300 to Power DSPs* application report (literature number SLVA088)]. A Schottky diode can also be used to tie the core rail to the I/O rail, effectively pulling up the I/O power supply to a level that can help initialize the logic within the DSP.

Core and I/O supply voltage regulators should be located close to the DSP (or DSP array) to minimize inductance and resistance in the power delivery path. Additionally, when designing for high-performance applications utilizing the C6000<sup>™</sup> platform of DSPs, the PC board should include separate power planes for core, I/O, and ground, all bypassed with high-quality low-ESL/ESR capacitors.



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absolute maximum ratings over operating case temperature range (unle	ss otherwise noted) <sup>†</sup>
Supply voltage range, CV <sub>DD</sub> (see Note 1)	
Supply voltage range, DV <sub>DD</sub> (see Note 1)	-0.3 V to 4 V
Input voltage range	-0.3 V to 4 V
Output voltage range	-0.3 V to 4 V
Operating case temperature range T <sub>C</sub> : (S temp version)	
(W temp version)	55°C to 115°C
Storage temperature range, T <sub>stg</sub>	55°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
NOTE 1: All voltage values are with respect to V<sub>SS</sub>.

#### recommended operating conditions

				C6201B			
			MIN	NOM	MAX	UNIT	
$CV_{DD}$	Supply voltage		1.71	1.8	1.89	V	
$DV_DD$	Supply voltage		3.14	3.30	3.46	V	
V <sub>SS</sub>	Supply ground		0	0	0	V	
V <sub>IH</sub>	High-level input voltage		2.0			V	
VIL	Low-level input voltage				0.8	V	
I <sub>OH</sub>	High-level output current				-12	mA	
I <sub>OL</sub>	Low-level output current				12	mA	
-	<b>T O U U U U</b>	S temp version	-40		90	°C	
т <sub>с</sub>	Operating case temperature <sup>‡</sup>	W temp version	-55		115	0	

<sup>‡</sup> Case temperature is measured at package bottom. There is no direct thermal path from the chip through the lid.



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# electrical characteristics over recommended ranges of supply voltage and operating case temperature (unless otherwise noted)

			(	C6201B		
PARAMETER $V_{OH}$ High-level output voltage $V_{OL}$ Low-level output voltage $I_1$ Input current <sup>†</sup> $I_{OZ}$ Off-state output current $I_{DD2V}$ Supply current, CPU + CPU memory access <sup>‡</sup> $I_{DD2V}$ Supply current, peripherals <sup>§</sup> $I_{DD3V}$ Supply current, I/O pins <sup>¶</sup> $C_i$ Input capacitance	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
V <sub>OH</sub>	High-level output voltage	DV <sub>DD</sub> = MIN, I <sub>OH</sub> = MAX	2.4			V
V <sub>OL</sub>	Low-level output voltage	$DV_{DD} = MIN,$ $I_{OL} = MAX$			0.6	V
l <sub>l</sub>	Input current <sup>†</sup>	$V_{I} = V_{SS}$ to $DV_{DD}$			±10	uA
I <sub>OZ</sub>	Off-state output current	$V_{O} = DV_{DD} \text{ or } 0 \text{ V}$			±10	uA
I <sub>DD2V</sub>	Supply current, CPU + CPU memory access <sup>‡</sup>	CV <sub>DD</sub> = NOM, CPU clock = 167 MHz		380		mA
I <sub>DD2V</sub>	Supply current, peripherals <sup>§</sup>	CV <sub>DD</sub> = NOM, CPU clock = 167 MHz		240		mA
I <sub>DD3V</sub>	Supply current, I/O pins <sup>¶</sup>	DV <sub>DD</sub> = NOM, CPU clock = 167 MHz		90		mA
Ci	Input capacitance				15	pF
Co	Output capacitance				15	pF

<sup>†</sup> TMS and TDI are not included due to internal pullups.

TRST is not included due to internal pulldown.

<sup>‡</sup> Measured with average CPU activity:

50% of time: 8 instructions per cycle, 32-bit DMEM access per cycle

50% of time: 2 instructions per cycle, 16-bit DMEM access per cycle

§ Measured with average peripheral activity:

50% of time: Timers at max rate, McBSPs at E1 rate, and DMA burst transfer between DMEM and SDRAM 50% of time: Timers at max rate, McBSPs at E1 rate, and DMA servicing McBSPs

<sup>¶</sup> Measured with average I/O activity (30-pF load):

25% of time: Reads from external SDRAM

25% of time: Writes to external SDRAM

50% of time: No activity



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# Tester Pin Electronics $V_{ref}$ $C_T = 30 \text{ pF}^{\dagger}$ $I_{OH}$ $I_{OH}$

PARAMETER MEASUREMENT INFORMATION

<sup>†</sup> Typical distributed load circuit capacitance

Figure 7. TTL-Level Outputs

#### signal transition levels

All input and output timing parameters are referenced to 1.5 V for both "0" and "1" logic levels.



Figure 8. Input and Output Voltage Reference Levels for AC Timing Measurements



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#### INPUT AND OUTPUT CLOCKS

#### timing requirements for CLKIN (see Figure 9)

				C6201	B-15			C620	1B-20		
NO.			CLKN = X		CLKN = >		CLKN = X		CLKN = >		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
1	t <sub>c(CLKIN)</sub>	Cycle time, CLKIN	26.7		6.67		20	S.	5	6	ns
2	t <sub>w(CLKINH)</sub>	Pulse duration, CLKIN high	*9.8		*2.7		*8	S. Ca	*2.35	N.M.	ns
3	t <sub>w(CLKINL)</sub>	Pulse duration, CLKIN low	*9.8		*2.7		*8		*2.35		ns
4	t <sub>t</sub> (CLKIN)	Transition time, CLKIN		*5		*0.6	8.	*5	8	*0.6	ns

\*Not production tested.



#### Figure 9. CLKIN Timings

#### switching characteristics for CLKOUT1<sup>†‡</sup> (see Figure 10)

				C620	D1B		
NO.		PARAMETER		DE = x4	CLKMOD	UNIT	
			MIN	MAX	MIN	MAX	
1	t <sub>c(CKO1)</sub>	Cycle time, CLKOUT1	*P - 0.7	*P + 0.7	*P - 0.7	*P + 0.7	ns
2	t <sub>w(CKO1H)</sub>	Pulse duration, CLKOUT1 high	*(P/2) - 0.5	*(P/2) + 0.5	*PH - 0.5	*PH + 0.5	ns
3	t <sub>w(CKO1L)</sub>	Pulse duration, CLKOUT1 low	*(P/2) - 0.5	*(P/2) + 0.5	*PL - 0.5	*PL + 0.5	ns
4	t <sub>t(CKO1)</sub>	Transition time, CLKOUT1		*0.6		*0.6	ns

 $^\dagger$  PH is the high period of CLKIN in ns and PL is the low period of CLKIN in ns.

<sup>‡</sup> P = 1/CPU clock frequency in nanoseconds (ns).







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## INPUT AND OUTPUT CLOCKS (CONTINUED)

# switching characteristics for CLKOUT2<sup>†</sup> (see Figure 11)

		C62	D1B	
NO.	PARAMETER	MIN	MAX	UNIT
1	t <sub>c(CKO2)</sub> Cycle time, CLKOUT2	*2P - 0.7	*2P + 0.7	ns
2	t <sub>w(CKO2H)</sub> Pulse duration, CLKOUT2 high	*P - 0.9	*P + 0.7	ns
3	t <sub>w(CKO2L)</sub> Pulse duration, CLKOUT2 low	*P - 0.7	*P + 0.9	ns
4	t <sub>t(CKO2)</sub> Transition time, CLKOUT2		*0.6	ns

<sup>†</sup> P = 1/CPU clock frequency in ns.







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### INPUT AND OUTPUT CLOCKS (CONTINUED)

#### SDCLK, SSCLK timing parameters

SDCLK timing parameters are the same as CLKOUT2 parameters.

SSCLK timing parameters are the same as CLKOUT1 or CLKOUT2 parameters, depending on SSCLK configuration.

# switching characteristics for the relation of SSCLK, SDCLK, and CLKOUT2 to CLKOUT1 (see Figure 12)<sup> $\dagger$ </sup>

		C62			
NO.		PARAMETER	MIN	MAX	UNIT
1	t <sub>d(CKO1-SSCLK)</sub>	Delay time, CLKOUT1 edge to SSCLK edge	(P/2) + 0.2	(P/2) + 4.2	ns
2	td(CKO1-SSCLK1/2)	Delay time, CLKOUT1 edge to SSCLK edge (1/2 clock rate)	(P/2) - 1	(P/2) + 2.4	ns
3	t <sub>d(CKO1-CKO2)</sub>	Delay time, CLKOUT1 edge to CLKOUT2 edge	*(P/2) - 1	*(P/2) + 2.4	ns
4	t <sub>d(CKO1-SDCLK)</sub>	Delay time, CLKOUT1 edge to SDCLK edge	(P/2) - 1	(P/2) + 2.4	ns

<sup>†</sup> P = 1/CPU clock frequency in ns.



Figure 12. Relation of CLKOUT2, SDCLK, and SSCLK to CLKOUT1



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### **ASYNCHRONOUS MEMORY TIMING**

### timing requirements for asynchronous memory cycles<sup>†</sup> (see Figure 13 and Figure 14)

NO.			C6201B		
			MIN MAX		UNIT
6	t <sub>su(EDV-CKO1H)</sub>	Setup time, read EDx valid before CLKOUT1 high	4.0		ns
7	t <sub>h(CKO1H-EDV)</sub>	Hold time, read EDx valid after CLKOUT1 high	0.8		ns
10	t <sub>su(ARDY-CKO1H)</sub>	Setup time, ARDY valid before CLKOUT1 high	3.0		ns
11	t <sub>h(CKO1H-ARDY)</sub>	Hold time, ARDY valid after CLKOUT1 high	1.8		ns

<sup>†</sup> To ensure data setup time, simply program the strobe width wide enough. ARDY is internally synchronized. If ARDY does meet setup or hold time, it may be recognized in the current cycle or the next cycle. Thus, ARDY can be an asynchronous input.

#### switching characteristics for asynchronous memory cycles<sup>‡</sup> (see Figure 13 and Figure 14)

NO.	PARAMETER		C6201B		
			MIN	MAX	UNIT
1	t <sub>d(CKO1H-CEV)</sub>	Delay time, CLKOUT1 high to CEx valid	-0.2	4.0	ns
2	t <sub>d(CKO1H-BEV)</sub>	Delay time, CLKOUT1 high to BEx valid		4.0	ns
3	t <sub>d(CKO1H-BEIV)</sub>	Delay time, CLKOUT1 high to BEx invalid	*-0.2		ns
4	t <sub>d(CKO1H-EAV)</sub>	Delay time, CLKOUT1 high to EAx valid		4.0	ns
5	t <sub>d(CKO1H-EAIV)</sub>	Delay time, CLKOUT1 high to EAx invalid	*-0.2		ns
8	t <sub>d(CKO1H-AOEV)</sub>	Delay time, CLKOUT1 high to AOE valid	-0.2	4.0	ns
9	t <sub>d(CKO1H-AREV)</sub>	Delay time, CLKOUT1 high to ARE valid	-0.2	4.0	ns
12	t <sub>d(CKO1H-EDV)</sub>	Delay time, CLKOUT1 high to EDx valid		4.0	ns
13	t <sub>d(CKO1H-EDIV)</sub>	Delay time, CLKOUT1 high to EDx invalid	*-0.2		ns
14	t <sub>d(CKO1H-AWEV)</sub>	Delay time, CLKOUT1 high to AWE valid	-0.2	4.0	ns

<sup>‡</sup> The minimum delay is also the minimum output hold after CLKOUT1 high.



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### **ASYNCHRONOUS MEMORY TIMING (CONTINUED)**





Figure 14. Asynchronous Memory Write Timing



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### SYNCHRONOUS-BURST MEMORY TIMING

#### timing requirements for synchronous-burst SRAM cycles (full-rate SSCLK) (see Figure 15)

NO			C6201B	
NO.		MIN	MIN MAX	
7	t <sub>su(EDV-SSCLKH)</sub> Setup time, read EDx va	alid before SSCLK high 1.7		ns
8	t <sub>h(SSCLKH-EDV)</sub> Hold time, read EDx val	lid after SSCLK high 1.5		ns

# switching characteristics for synchronous-burst SRAM cycles<sup>†</sup> (full-rate SSCLK) (see Figure 15 and Figure 16)

NO.	PARAMETER		C6201B	UNIT
			MIN MAX	
1	t <sub>osu(CEV-SSCLKH)</sub>	Output setup time, CEx valid before SSCLK high	0.5P - 1.3	ns
2	t <sub>oh(SSCLKH-CEV)</sub>	Output hold time, CEx valid after SSCLK high	0.5P - 2.3	ns
3	t <sub>osu(BEV-SSCLKH)</sub>	Output setup time, BEx valid before SSCLK high	0.5P - 1.3	ns
4	t <sub>oh</sub> (SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	*0.5P - 2.3	ns
5	t <sub>osu(EAV-SSCLKH)</sub>	Output setup time, EAx valid before SSCLK high	0.5P - 1.3	ns
6	t <sub>oh</sub> (SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	*0.5P - 2.3	ns
9	t <sub>osu(ADSV-SSCLKH)</sub>	Output setup time, SSADS valid before SSCLK high	0.5P - 1.3	ns
10	t <sub>oh(SSCLKH-ADSV)</sub>	Output hold time, SSADS valid after SSCLK high	0.5P - 2.3	ns
11	t <sub>osu(OEV-SSCLKH)</sub>	Output setup time, SSOE valid before SSCLK high	0.5P - 1.3	ns
12	t <sub>oh(SSCLKH-OEV)</sub>	Output hold time, SSOE valid after SSCLK high	0.5P - 2.3	ns
13	t <sub>osu(EDV-SSCLKH)</sub>	Output setup time, EDx valid before SSCLK high	0.5P - 1.3	ns
14	t <sub>oh</sub> (SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	*0.5P - 2.3	ns
15	t <sub>osu(WEV-SSCLKH)</sub>	Output setup time, SSWE valid before SSCLK high	0.5P - 1.3	ns
16	t <sub>oh(SSCLKH-WEV)</sub>	Output hold time, SSWE valid after SSCLK high	0.5P - 2.3	ns

<sup>†</sup> When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1, 0.5P is defined as PH (pulse duration of CLKIN high) for all output setup times; 0.5P is defined as PL (pulse duration of CLKIN low) for all output hold times.


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#### SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)





Figure 16. SBSRAM Write Timing (Full-Rate SSCLK)



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## SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

# timing requirements for synchronous-burst SRAM cycles (half-rate SSCLK) (see Figure 17)

NIC			C6201B	
NO.			MIN MAX	UNIT
7	t <sub>su(EDV-SSCLKH)</sub>	Setup time, read EDx valid before SSCLK high	2.5	ns
8	t <sub>h(SSCLKH-EDV)</sub>	Hold time, read EDx valid after SSCLK high	1.5	ns

# switching characteristics for synchronous-burst SRAM cycles<sup>†</sup> (half-rate SSCLK) (see Figure 17 and Figure 18)

NO	DADAMETED		C6201B	
NO.		PARAMETER	MIN MAX	UNIT
1	t <sub>osu(CEV-SSCLKH)</sub>	Output setup time, CEx valid before SSCLK high	1.5P - 3	ns
2	t <sub>oh(SSCLKH-CEV)</sub>	Output hold time, CEx valid after SSCLK high	0.5P - 1.5	ns
3	t <sub>osu(BEV-SSCLKH)</sub>	Output setup time, BEx valid before SSCLK high	1.5P - 3	ns
4	t <sub>oh(SSCLKH-BEIV)</sub>	Output hold time, BEx invalid after SSCLK high	*0.5P - 1.5	ns
5	t <sub>osu(EAV-SSCLKH)</sub>	Output setup time, EAx valid before SSCLK high	1.5P - 3 🎢	ns
6	t <sub>oh(SSCLKH-EAIV)</sub>	Output hold time, EAx invalid after SSCLK high	*0.5P - 1.5	ns
9	t <sub>osu(ADSV-SSCLKH)</sub>	Output setup time, SSADS valid before SSCLK high	1.5P - 3	ns
10	t <sub>oh(SSCLKH-ADSV)</sub>	Output hold time, SSADS valid after SSCLK high	0.5P - 1.5	ns
11	t <sub>osu(OEV-SSCLKH)</sub>	Output setup time, SSOE valid before SSCLK high	1.5P - 3	ns
12	t <sub>oh(SSCLKH-OEV)</sub>	Output hold time, SSOE valid after SSCLK high	0.5P - 1.5	ns
13	t <sub>osu(EDV-SSCLKH)</sub>	Output setup time, EDx valid before SSCLK high	1.5P - 3	ns
14	t <sub>oh(SSCLKH-EDIV)</sub>	Output hold time, EDx invalid after SSCLK high	*0.5P - 1.5	ns
15	t <sub>osu(WEV-SSCLKH)</sub>	Output setup time, SSWE valid before SSCLK high	1.5P - 3	ns
16	t <sub>oh(SSCLKH-WEV)</sub>	Output hold time, SSWE valid after SSCLK high	0.5P - 1.5	ns

<sup>†</sup> When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1:

1.5P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

0.5P = PL, where PL = pulse duration of CLKIN low.

\*Not production tested.



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#### SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)



Figure 18. SBSRAM Write Timing (1/2 Rate SSCLK)



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## SYNCHRONOUS DRAM TIMING

#### timing requirements for synchronous DRAM cycles (see Figure 19)

		C6201B	
NO.		MIN MAX	UNIT
7	t <sub>su(EDV-SDCLKH)</sub> Setup time, read EDx valid before SDCLK high	0.5	ns
8	t <sub>h(SDCLKH-EDV)</sub> Hold time, read EDx valid after SDCLK high	3	ns

## switching characteristics for synchronous DRAM cycles<sup>†</sup> (see Figure 19-Figure 24)

			C6201B	
NO.		PARAMETER	MIN MAX	UNIT
1	t <sub>osu(CEV-SDCLKH)</sub>	Output setup time, CEx valid before SDCLK high	1.5P - 3.5	ns
2	t <sub>oh(SDCLKH-CEV)</sub>	Output hold time, CEx valid after SDCLK high	0.5P - 1	ns
3	t <sub>osu(BEV-SDCLKH)</sub>	Output setup time, BEx valid before SDCLK high	1.5P - 3.5	ns
4	t <sub>oh</sub> (SDCLKH-BEIV)	Output hold time, BEx invalid after SDCLK high	*0.5P - 1	ns
5	t <sub>osu(EAV-SDCLKH)</sub>	Output setup time, EAx valid before SDCLK high	1.5P - 3.5	ns
6	t <sub>oh</sub> (SDCLKH-EAIV)	Output hold time, EAx invalid after SDCLK high	*0.5P - 1	ns
9	t <sub>osu(SDCAS-SDCLKH)</sub>	Output setup time, SDCAS valid before SDCLK high	1.5P - 3.5	ns
10	t <sub>oh(SDCLKH-SDCAS)</sub>	Output hold time, SDCAS valid after SDCLK high	0.5P - 1	ns
11	t <sub>osu(EDV-SDCLKH)</sub>	Output setup time, EDx valid before SDCLK high	1.5P - 3.5	ns
12	t <sub>oh(SDCLKH-EDIV)</sub>	Output hold time, EDx invalid after SDCLK high	*0.5P - 1	ns
13	t <sub>osu(SDWE-SDCLKH)</sub>	Output setup time, SDWE valid before SDCLK high	1.5P - 3.5	ns
14	t <sub>oh</sub> (SDCLKH-SDWE)	Output hold time, SDWE valid after SDCLK high	0.5P - 1	ns
15	t <sub>osu(SDA10V-SDCLKH)</sub>	Output setup time, SDA10 valid before SDCLK high	1.5P - 3.5	ns
16	t <sub>oh</sub> (SDCLKH-SDA10IV)	Output hold time, SDA10 invalid after SDCLK high	*0.5P - 1	ns
17	t <sub>osu(SDRAS-SDCLKH)</sub>	Output setup time, SDRAS valid before SDCLK high	1.5P - 3.5	ns
18	t <sub>oh(SDCLKH-SDRAS)</sub>	Output hold time, SDRAS valid after SDCLK high	0.5P - 1	ns

<sup>†</sup> When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1:

1.5P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

0.5P = PL, where PL = pulse duration of CLKIN low.

\*Not production tested.

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## SYNCHRONOUS DRAM TIMING (CONTINUED)





Figure 20. Three SDRAM WRT Commands



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## SYNCHRONOUS DRAM TIMING (CONTINUED)

Figure 24. SDRAM MRS Command



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## HOLD/HOLDA TIMING

#### timing requirements for the HOLD/HOLDA cycles<sup>†</sup> (see Figure 25)

NO		C6201B	
NO.		MIN MAX	UNIT
1	t <sub>su(HOLDH-CKO1H)</sub> Setup time, HOLD high before CLKOUT1 high	*1	ns
2	t <sub>h(CKO1H-HOLDL)</sub> Hold time, HOLD low after CLKOUT1 high	*4	ns

<sup>+</sup> HOLD is synchronized internally. Therefore, if setup and hold times are not met, it will either be recognized in the current cycle or in the next cycle. Thus, HOLD can be an asynchronous input.

\*Not production tested.

## switching characteristics for the HOLD/HOLDA cycles<sup>‡</sup> (see Figure 25)

	PARAMETER		C620		
NO.			MIN	MAX	UNIT
3	t <sub>R(HOLDL-BHZ)</sub>	Response time, HOLD low to EMIF Bus high impedance	*4P	ş	ns
4	t <sub>R(BHZ-HOLDAL)</sub>	Response time, EMIF Bus high impedance to HOLDA low	*P	*2P	ns
5	t <sub>R(HOLDH-HOLDAH)</sub>	Response time, HOLD high to HOLDA high	*4P	*7P	ns
6	t <sub>d(CKO1H-HOLDAL)</sub>	Delay time, CLKOUT1 high to HOLDA valid	*1	8	ns
7	t <sub>d(CKO1H-BHZ)</sub>	Delay time, CLKOUT1 high to EMIF Bus high impedance <sup>¶</sup>	*3	*11	ns
8	t <sub>d(CKO1H-BLZ)</sub>	Delay time, CLKOUT1 high to EMIF Bus low impedance <sup>¶</sup>	*3	*11	ns
9	t <sub>R(HOLDH-BLZ)</sub>	Response time, HOLD high to EMIF Bus low impedance	*3P	*6P	ns

<sup>‡</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

\*Not production tested.

§ All pending EMIF transactions are allowed to complete before HOLDA is asserted. The worst cases for this is an asynchronous read or write with external ARDY used or a minimum of eight consecutive SDRAM reads or writes when RBTR8 = 1. If no bus transactions are occurring, then the minimum delay time can be achieved. Also, bus hold can be indefinitely delayed by setting NOHOLD = 1.

<sup>1</sup> EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.



<sup>†</sup> EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.

#### Figure 25. HOLD/HOLDA Timing



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#### **RESET TIMING**

#### timing requirements for reset (see Figure 26)

			C6201B		
NO.			MIN	MAX	UNIT
1	t <sub>w(RST)</sub>	Width of the RESET pulse (PLL stable) <sup>†</sup>	*10		CLKOUT1 cycles
		Width of the $\overline{RESET}$ pulse (PLL needs to sync up) <sup>‡</sup>	250		μs

<sup>†</sup> This parameter applies to CLKMODE x1 when CLKIN is stable and applies to CLKMODE x4 when CLKIN and PLL are stable.

<sup>‡</sup> This parameter only applies to CLKMODE x4. The RESET signal is not connected internally to the clock PLL circuit. The PLL, however, may need up to 250 µs to stabilize following device power up or after PLL configuration has been changed. During that time, RESET must be asserted to ensure proper device operation. See the *clock PLL* section for PLL lock times.

\*Not production tested.

#### switching characteristics during reset<sup>§¶</sup> (see Figure 26)

	PARAMETER	C6201B				
NO.		MIN	MAX	UNIT		
2	t <sub>R(RST)</sub>	Response time to change of value in RESET signal		2		CLKOUT1 cycles
3	t <sub>d(CKO1H-CKO2IV)</sub>	Delay time, CLKOUT1 high to CLKOUT2 invalid		*-1		ns
4	t <sub>d(CKO1H-CKO2V)</sub>	Delay time, CLKOUT1 high to CLKOUT2 valid			10	ns
5	t <sub>d(CKO1H-SDCLKIV)</sub>	Delay time, CLKOUT1 high to SDCLK invalid		*-1		ns
6	t <sub>d(CKO1H-SDCLKV)</sub>	Delay time, CLKOUT1 high to SDCLK valid			10	ns
7	t <sub>d(CKO1H-SSCKIV)</sub>	Delay time, CLKOUT1 high to SSCLK invalid		*-1		ns
8	t <sub>d(CKO1H-SSCKV)</sub>	Delay time, CLKOUT1 high to SSCLK valid			10	ns
9	t <sub>d(CKO1H-LOWIV)</sub>	Delay time, CLKOUT1 high to low group invalid		*-1		ns
10	t <sub>d(CKO1H-LOWV)</sub>	Delay time, CLKOUT1 high to low group valid			*10	ns
11	t <sub>d(CKO1H-HIGHIV)</sub>	Delay time, CLKOUT1 high to high group invalid		*-1		ns
12	t <sub>d(CKO1H-HIGHV)</sub>	Delay time, CLKOUT1 high to high group valid			*10	ns
13	t <sub>d(CKO1H-ZHZ)</sub>	Delay time, CLKOUT1 high to Z group high impedance		*-1		ns
14	t <sub>d(CKO1H-ZV)</sub>	Delay time, CLKOUT1 high to Z group valid			*10	ns
l ow a	roun consists of	IACK INUM[3:0] DMAC[3:0] PD TOUTO and TOUT1				

§ Low group consists of: High group consists of: Z group consists of:

IACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1

HINT

EA[21:2], ED[31:0], CE[3:0], BE[3:0], ARE, AWE, AOE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, SDWE, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.

<sup>¶</sup> HRDY is gated by input HCS.

If  $\overline{HCS} = 0$  at device reset,  $\overline{HRDY}$  belongs to the high group.

If  $\overline{HCS} = 1$  at device reset,  $\overline{HRDY}$  belongs to the low group.

\*Not production tested.



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**RESET TIMING (CONTINUED)** 

<sup>‡</sup> HRDY is gated by input HCS.

If  $\overline{HCS} = 0$  at device reset,  $\overline{HRDY}$  belongs to the high group.

If  $\overline{HCS} = 1$  at device reset,  $\overline{HRDY}$  belongs to the low group.

#### Figure 26. Reset Timing



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## **EXTERNAL INTERRUPT TIMING**

## timing requirements for interrupt response cycles<sup>†‡</sup> (see Figure 27)

			C6201B		
NO.		MIN	MAX	UNIT	
2	t <sub>w(ILOW)</sub> Width of the interrupt pulse low	*2P		ns	
3	t <sub>w(IHIGH)</sub> Width of the interrupt pulse high	*2P		ns	

<sup>†</sup> Interrupt signals are synchronized internally and are potentially recognized one cycle later if setup and hold times are violated. Thus, they can be connected to asynchronous inputs.

 $^{\ddagger}$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

\*Not production tested.

#### switching characteristics during interrupt response cycles<sup>§</sup> (see Figure 27)

NO.	DADAWETED	C6201B		
	PARAMETER		MAX	UNIT
1	t <sub>R(EINTH-IACKH)</sub> Response time, EXT_INTx high to IACK high	*9P		ns
4	t <sub>d(CKO2L-IACKV)</sub> Delay time, CLKOUT2 low to IACK valid	*-4	6	ns
5	t <sub>d(CKO2L-INUMV)</sub> Delay time, CLKOUT2 low to INUMx valid		6	ns
6	t <sub>d(CKO2L-INUMIV)</sub> Delay time, CLKOUT2 low to INUMx invalid	*-4		ns

P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

When the PLL is used (CLKMODE x4),  $0.5P = 1/(2 \times CPU \text{ clock frequency})$ .

For CLKMODE x1: 0.5P = PH, where PH is the high period of CLKIN.

\*Not production tested.



Figure 27. Interrupt Timing



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## HOST-PORT INTERFACE TIMING

# timing requirements for host-port interface cycles<sup>†‡</sup> (see Figure 28, Figure 29, Figure 30, and Figure 31)

			C6201B		
NO.			MIN	MAX	UNIT
1	t <sub>su(SEL-HSTBL)</sub>	Setup time, select signals <sup>§</sup> valid before HSTROBE low	4		ns
2	t <sub>h(HSTBL-SEL)</sub>	Hold time, select signals <sup>§</sup> valid after HSTROBE low	2		ns
3	t <sub>w(HSTBL)</sub>	Pulse duration, HSTROBE low	2P		ns
4	t <sub>w(HSTBH)</sub>	Pulse duration, HSTROBE high between consecutive accesses	*2P		ns
10	t <sub>su(SEL-HASL)</sub>	Setup time, select signals <sup>§</sup> valid before HAS low	4		ns
11	t <sub>h(HASL-SEL)</sub>	Hold time, select signals <sup>§</sup> valid after HAS low	2		ns
12	t <sub>su(HDV-HSTBH)</sub>	Setup time, host data valid before HSTROBE high	4		ns
13	t <sub>h(HSTBH-HDV)</sub>	Hold time, host data valid after HSTROBE high	2		ns
14	t <sub>h(HRDYL-HSTBL)</sub>	Hold time, HSTROBE low after HRDY low. HSTROBE shoul not be inactivated until HRDY is active (low); otherwise, HPI writes will not complete properly.	*1		ns
18	t <sub>su(HASL-HSTBL)</sub>	Setup time, HAS low before HSTROBE low	*2		ns
19	t <sub>h(HSTBL-HASL)</sub>	Hold time, HAS low after HSTROBE low	*2		ns

<sup>†</sup> HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

<sup>‡</sup> The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

§ Select signals include: HCNTRL[1:0], HR/W, and HHWIL.

\*Not production tested.

# switching characteristics during host-port interface cycles<sup>†‡</sup> (see Figure 28, Figure 29, Figure 30, and Figure 31)

NO	DADAMETED	C62			
NO.	PARAMETER		MIN	MAX	UNIT
5	t <sub>d(HCS-HRDY)</sub>	Delay time, HCS to HRDY <sup>1</sup>	*1	9	ns
6	t <sub>d(HSTBL-HRDYH)</sub>	Delay time, HSTROBE low to HRDY high#	*3	12	ns
7	t <sub>oh(HSTBL-HDLZ)</sub>	Output hold time, HD low impedance after HSTROBE low for an HPI read	*4		ns
8	t <sub>d(HDV-HRDYL)</sub>	Delay time, HD valid to HRDY low	*P - 3	*P + 3	ns
9	t <sub>oh(HSTBH-HDV)</sub>	Output hold time, HD valid after HSTROBE high	*1	*12	ns
15	t <sub>d(HSTBH-HDHZ)</sub>	Delay time, HSTROBE high to HD high impedance	*3	*12	ns
16	t <sub>d(HSTBL-HDV)</sub>	Delay time, HSTROBE low to HD valid	*2	*12	ns
17	t <sub>d(HSTBH-HRDYH)</sub>	Delay time, HSTROBE high to HRDY high <sup>  </sup>	*3	12	ns

<sup>†</sup> HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

<sup>‡</sup> The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>1</sup> HCS enables HRDY, and HRDY is always low when HCS is high. The case where HRDY goes high when HCS falls indicates that HPI is busy completing a previous HPID write or READ with autoincrement.

<sup>#</sup> This parameter is used during an HPID read. At the beginning of the first half-word transfer on the falling edge of HSTROBE, the HPI sends the request to the DMA auxiliary channel, and HRDY remains high until the DMA auxiliary channel loads the requested data into HPID.

This parameter is used after the second half-word of an HPID write or autoincrement read. HRDY remains low if the access is not an HPID write or autoincrement read. Reading or writing to HPIC or HPIA does not affect the HRDY signal.

\*Not production tested.



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## HOST-PORT INTERFACE TIMING (CONTINUED)

<sup>†</sup> HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.





Figure 29. HPI Read Timing (HAS Used)



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## HOST-PORT INTERFACE TIMING (CONTINUED)

<sup>†</sup> HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.





<sup>+</sup> HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 31. HPI Write Timing (HAS Used)y



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## **MULTICHANNEL BUFFERED SERIAL PORT TIMING**

## timing requirements for McBSP<sup>†‡</sup>(see Figure 32)

				C620	D1B	
NO.				MIN	MAX	UNIT
2	t <sub>c(CKRX)</sub>	Cycle time, CLKR/X	CLKR/X ext	*2P		ns
3	t <sub>w(CKRX)</sub>	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X ext	*P - 1		ns
-		Octor time, external ECD bisk before OLKD law	CLKR int	*9		
5 t <sub>su(FRH</sub>	t <sub>su</sub> (FRH-CKRL)	Setup time, external FSR high before CLKR low	CLKR ext	2		ns
			CLKR int	*6		
6	t <sub>h(CKRL-FRH)</sub> Hole	Hold time, external FSR high after CLKR low	CLKR ext	3		ns
-		Octore times DB visited to face OLICB law	CLKR int 8			
7	t <sub>su</sub> (DRV-CKRL)	Setup time, DR valid before CLKR low	CLKR ext	1		ns
			CLKR int	3		
8	<sup>t</sup> h(CKRL-DRV)	Hold time, DR valid after CLKR low	CLKR ext	4		ns
10			CLKX int	9		
10	t <sub>su</sub> (FXH-CKXL)	Setup time, external FSX high before CLKX low	CLKX ext	2		ns
		Held time, as targed FOV bish offer OLIV law	CLKX int	6		
11	t <sub>h(CKXL-FXH)</sub>	Hold time, external FSX high after CLKX low	CLKX ext	3		ns

<sup>†</sup> CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted.  $^{\ddagger}$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. \*Not production tested



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## **MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)**

## switching characteristics for McBSP<sup>†‡§</sup> (see Figure 32)

				C620	1B	
NO.		PARAMETER		MIN	MAX	UNIT
1	t <sub>d</sub> (CKSH-CKRXH)	Delay time, CLKS high to CLKR/X high for internal CLKR/X generated from CLKS input		3	10	ns
2	t <sub>c(CKRX)</sub>	Cycle time, CLKR/X	CLKR/X int	2P		ns
3	t <sub>w(CKRX)</sub>	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X int	*C - 1.6 <sup>¶</sup>	*C + 1 <sup>¶</sup>	ns
4	t <sub>d(CKRH-FRV)</sub>	Delay time, CLKR high to internal FSR valid	CLKR int	*-2.5	3	ns
	t <sub>d(CKXH-FXV)</sub>	H-FXV) Delay time, CLKX high to internal FSX valid	CLKX int	*-2	3	20
9			CLKX ext	*3	*9	ns
		Disable time, DX high impedance following last data bit from	CLKX int	*-1	*4	
12	t <sub>dis(CKXH-DXHZ)</sub>	CLKX high	CLKX ext	*3	*9	ns
			CLKX int	*-1	*4	
13	t <sub>d</sub> (CKXH-DXV)	Delay time, CLKX high to DX valid	CLKX ext	*3	*9	ns
		Delay time, FSX high to DX valid	FSX int	*-1	*3	
14	t <sub>d(FXH-DXV)</sub>	ONLY applies when in data delay 0 (XDATDLY = 00b) mode	FSX ext	*3	*9	ns

<sup>†</sup> CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted. <sup>‡</sup> Minimum delay times also represent minimum output hold times.

§ P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

\*Not production tested.

<sup>¶</sup>C = HorL

S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P clks if CLKSM = 0 (P clks = CLKS period)

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero



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## MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)





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## MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

#### timing requirements for FSR when GSYNC = 1 (see Figure 33)

		C620	01B	
NO.		MIN	MAX	UNIT
1	t <sub>su(FRH-CKSH)</sub> Setup time, FSR high before CLKS high	4		ns
2	t <sub>h(CKSH-FRH)</sub> Hold time, FSR high after CLKS high	4		ns



Figure 33. FSR Timing When GSYNC = 1

#### timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 0<sup>†‡</sup> (see Figure 34)

				C62	01B		
NO.			MAST	ER	SLA\	/E	UNIT
			MIN	MAX	MIN	MAX	
4	t <sub>su(DRV-CKXL)</sub>	Setup time, DR valid before CLKX low	12		2 - 3P		ns
5	t <sub>h(CKXL-DRV)</sub>	Hold time, DR valid after CLKX low	4		5 + 6P		ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.



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## MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

#### switching characteristics for McBSP as SPI master or slave; CLKSTP = 10b, CLKXP = $0^{++}$ (see Figure 34)

				С	6201B		
NO.		PARAMETER	MASTER§		SL	UNIT	
			MIN	MAX	MIN	MAX	
1	t <sub>h(CKXL-FXL)</sub>	Hold time, FSX low after CLKX low <sup>¶</sup>	T - 2	*T + 3			ns
2	t <sub>d(FXL-CKXH)</sub>	Delay time, FSX low to CLKX high <sup>#</sup>	*L - 2	L + 3			ns
3	t <sub>d(CKXH-DXV)</sub>	Delay time, CLKX high to DX valid	*-2	4	*3P + 4	5P + 17	ns
6	t <sub>dis(CKXL-DXHZ)</sub>	Disable time, DX high impedance following last data bit from CLKX low	*L - 2	*L + 3			ns
7	t <sub>dis(FXH-DXHZ)</sub>	Disable time, DX high impedance following last data bit from FSX high			*P + 3	*3P + 17	ns
8	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid			*2P + 2	4P + 17	ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§ S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P clks if CLKSM = 0 (P clks = CLKS period)

T = CLKX period = (1 + CLKGDV) \* S

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero L = CLKX lov

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

<sup>1</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

\*Not production tested.

# FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).





<sup>1</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

# FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



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## **MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)**

#### timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0<sup>†‡</sup> (see Figure 35)

		C6201B					
NO.			MAS	TER	SLA	٧E	UNIT
			MIN	MAX	MIN	MAX	
4	t <sub>su(DRV-CKXH)</sub>	Setup time, DR valid before CLKX high	12		2 - 3P		ns
5	t <sub>h(CKXH-DRV)</sub>	Hold time, DR valid after CLKX high	4		5 + 6P		ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

# switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0<sup>†‡</sup> (see Figure 35)

				C62	201B		
NO.		PARAMETER	MAST	ER§	SL	UNIT	
			MIN	MAX	MIN	MAX	
1	t <sub>h(CKXL-FXL)</sub>	Hold time, FSX low after CLKX low <sup>¶</sup>	L - 2	*L + 3			ns
2	t <sub>d(FXL-CKXH)</sub>	Delay time, FSX low to CLKX high <sup>#</sup>	*T - 2	T + 3			ns
3	t <sub>d(CKXL-DXV)</sub>	Delay time, CLKX low to DX valid	*-2	4	*3P + 4	5P + 17	ns
6	t <sub>dis(CKXL-DXHZ)</sub>	Disable time, DX high impedance following last data bit from CLKX low	*-2	*4	*3P + 3	*5P + 17	ns
7	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid	*H - 2	H + 4	*2P + 2	4P + 17	ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§ S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P\_clks if CLKSM = 0 (P\_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) \* S

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

<sup>1</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

\*Not production tested.

<sup>#</sup> FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



Figure 35. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 0



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## MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

#### timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1<sup>†‡</sup> (see Figure 36)

			C6201B				
NO.			MASTER SLAVE		٧E	UNIT	
			MIN	MAX	MIN	MAX	
4	t <sub>su(DRV-CKXH)</sub>	Setup time, DR valid before CLKX high	12		2 - 3P		ns
5	t <sub>h(CKXH-DRV)</sub>	Hold time, DR valid after CLKX high	4		5 + 6P		ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

#### switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1<sup>†‡</sup> (see Figure 36)

				C62	201B		
NO.		PARAMETER	MASTER§		SL	UNIT	
			MIN	MAX	MIN	MAX	
1	t <sub>h(CKXH-FXL)</sub>	Hold time, FSX low after CLKX high <sup>¶</sup>	T - 2	*T + 3			ns
2	t <sub>d(FXL-CKXL)</sub>	Delay time, FSX low to CLKX low <sup>#</sup>	*H - 2	H + 3			ns
3	t <sub>d(CKXL-DXV)</sub>	Delay time, CLKX low to DX valid	*-2	4	*3P + 4	5P + 17	ns
6	t <sub>dis(CKXH-DXHZ)</sub>	Disable time, DX high impedance following last data bit from CLKX high	*H - 2	*H + 3			ns
7	t <sub>dis(FXH-DXHZ)</sub>	Disable time, DX high impedance following last data bit from FSX high			*P + 3	*3P + 17	ns
8	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid			*2P + 2	4P + 17	ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§ S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P\_clks if CLKSM = 0 (P\_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) \* S

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero L = CLKX

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

<sup>1</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

\*Not production tested.

<sup>#</sup> FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



Figure 36. McBSP Timing as SPI Master or Slave: CLKSTP = 10b, CLKXP = 1



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## **MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)**

#### timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1<sup>+‡</sup> (see Figure 37)

					C6201B			
NO.			MAS	TER	SLA	/E	UNIT	
			MIN	MAX	MIN	MAX		
4	t <sub>su(DRV-CKXL)</sub>	Setup time, DR valid before CLKX low	12		2 - 3P		ns	
5	t <sub>h(CKXL-DRV)</sub>	Hold time, DR valid after CLKX low	4		5 + 6P		ns	

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

# switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1<sup>†‡</sup> (see Figure 37)

				C6:	201B		
NO.		PARAMETER	MAST	<b>ER</b> §	SLA	UNIT	
			MIN	MAX	MIN	MAX	
1	t <sub>h(CKXH-FXL)</sub>	Hold time, FSX low after CLKX high <sup>¶</sup>	H - 2	*H + 3			ns
2	t <sub>d(FXL-CKXL)</sub>	Delay time, FSX low to CLKX low#	*T - 2	T + 1			ns
3	t <sub>d(CKXH-DXV)</sub>	Delay time, CLKX high to DX valid	*-2	4	*3P + 3	5P + 17	ns
6	t <sub>dis(CKXH-DXHZ)</sub>	Disable time, DX high impedance following last data bit from CLKX high	*-2	*4	*3P + 3	*5P + 17	ns
7	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid	*L - 2	L + 4	*2P + 2	4P + 17	ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

§ S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P clks if CLKSM = 0 (P clks = CLKS period)

T = CLKX period = (1 + CLKGDV) \* S

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

<sup>1</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

\*Not production tested.

# FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).



Figure 37. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 1



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#### DMAC, TIMER, POWER-DOWN TIMING

#### switching characteristics for DMAC outputs (see Figure 38)



Figure 38. DMAC Timing

#### timing requirements for timer inputs<sup>†</sup> (see Figure 39)

		C6201B		
NO.		MIN	I MAX	UNIT
1	t <sub>w(TINP)</sub> Pulse duration, TINP high or low	*2P		ns
<sup>†</sup> P = 1/0	CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.			

\*Not production tested.

#### switching characteristics for timer outputs (see Figure 39)

		C620			
NO.		MIN	MAX	UNIT	
2	t <sub>d(CKO1H-TOUTV)</sub>	Delay time, CLKOUT1 high to TOUT valid	*2	9	ns
*Not prod	duction tested.				



Figure 39. Timer Timing

#### switching characteristics for power-down outputs (see Figure 40)

		PABAMETER	C62		
NO.		MIN	MAX	UNIT	
1	t <sub>d(CKO1H-PDV)</sub>	*2	9	ns	
*Not pro	duction tested.				
	CLKOUT1 /			/	,
	PD				
		Figure 40. Power-Down Timing			



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## JTAG TEST-PORT TIMING

## timing requirements for JTAG test port (see Figure 41)

	C620			
	MIN	MAX	UNIT	
t <sub>c(TCK)</sub>	Cycle time, TCK	*50		ns
t <sub>su(TDIV-TCKH)</sub>	Setup time, TDI/TMS/TRST valid before TCK high	*10		ns
t <sub>h(TCKH-TDIV)</sub>	Hold time, TDI/TMS/TRST valid after TCK high	*5		ns
t	su(TDIV-TCKH)	Setup time, TDI/TMS/TRST valid before TCK high	MIN       cc(TCK)     Cycle time, TCK     *50       su(TDIV-TCKH)     Setup time, TDI/TMS/TRST valid before TCK high     *10	Cycle time, TCK *50   isu(TDIV-TCKH) Setup time, TDI/TMS/TRST valid before TCK high *10

\*Not production tested.

#### switching characteristics for JTAG test port (see Figure 41)

NO.	DADAMETED	C620		
	PARAMETER	MIN	MAX	UNIT
2	t <sub>d(TCKL-TDOV)</sub> Delay time, TCK low to TDO valid	*0	*15	ns

\*Not production tested.







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#### MECHANICAL DATA

#### CERAMIC BALL GRID ARRAY

#### GLP (S-CBGA-N429)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-156
- D. Flip chip application only
- E. For 320C6201B (1.8 V core device).
- F. Package weight for GLP is 7.65 grams.

#### thermal resistance characteristics (S-CBGA package)

NO			°C/W	Air Flow
1	$R\Theta_{JC}$	Junction-to-Case, measured to the bottom of solder ball	3.0	N/A
2	$R\Theta_{JC}$	Junction-to-Case, measured to the top of the package lid	7.3	N/A
3	$R\Theta_{JA}$	Junction-to-Ambient	14.5	0
4			11.8	150 fpm
5	R <sub>OJMA</sub>	Junction-to-Moving-Air	11.1	250 fpm
6			10.2	500 fpm
7	R <sub>ØJB</sub>	Junction-to-Board, measured by soldering a thermocouple to one of the middle traces on the board at the edge of the package	6.2	N/A





#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SMJ320C6201BGLPW15	OBSOLETE	CFCBGA	GLP	429		TBD	Call TI	Call TI	-55 to 115	5962-9857801QX A SMJ320C6201BGL PW15	

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(<sup>5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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## PACKAGE OPTION ADDENDUM

## **MECHANICAL DATA**

MCBG004A - SEPTEMBER 1998 - REVISED JANUARY 2002

#### **CERAMIC BALL GRID ARRAY**

#### GLP (S-CBGA-N429)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-156
- D. Flip chip application only



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